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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Kazuyoshi Okawa, et al.

Serial No.: 10/588,636

Filing Date: August 4, 2006

Art Unit: 2827

Title: Semiconductor Device Test
Apparatus and Method

April 30, 2007

Commissioner of Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

Pursuant to the duty of disclosure set forth in 37 CFR § 1.56, Applicants respectfully submit the following information disclosure statement.

The undersigned certifies that each of the following references was contained in a communication from a counterpart foreign application not more than three months prior to the filing of this statement.

The disclosed references are:

JP 2000-195294; Japanese Patent Office; published 7-14- 2000, with its English abstract.

JP 11-338521; Japanese Patent Office; published 12-10-1999, with its English abstract.

JP 03-102521; Japanese Patent Office; published 4-26-1991, with its English abstract.

JP 2002-216495, Japanese Patent Office; published 8-2-2002, with its English abstract.

Applicants respectfully request that the Examiner initial the cited references shown on the enclosed form PTO-1449 and that the references be made of record in the present application.

Respectfully submitted,



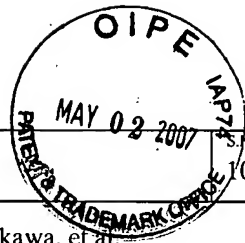
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Enc. PTO Form SB1449, Cited Refs (4),
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Certificate of Mailing Under 37 CFR 1.8

I certify that this Information Disclosure Statement and any enclosed materials are being deposited with the United States Postal Service on April 30, 2007 with sufficient postage as first class mail in an envelope addressed to Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.



David N. Lathrop



Substitute Form PTO-1449

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10/588,636

INFORMATION DISCLOSURE STATEMENT

APPLICANT
Kazuyoshi Okawa, et al.FILING DATE
August 4, 2006GROUP
2827

U.S. PATENT DOCUMENTS

*Exam. Initial	Cite No.	DOCUMENT NUMBER Number - Kind Code	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	FILING DATE
		US-			
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FOREIGN PATENT DOCUMENTS

*Exam. Initial	Cite No.	DOCUMENT NUMBER Number - Kind Code	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	TRANSLATION YES NO	
		JP 2000-195294	7-14- 2000	JAPAN, with its English abstract		X
		JP 11-338521	12-10-1999	JAPAN, with its English abstract		X
		JP 03-102521	4-26-1991	JAPAN, with its English abstract		X
		JP 2002-216495	8-2-2002	JAPAN, with its English abstract		X

NON-PATENT LITERATURE DOCUMENTS

*Exam. Initial	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	TRANSLATION YES NO	

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP; draw line through citation if not in conformance and not considered. Include copy of this form with next communication with applicant.